								R	EVIS	IONS										
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PMIC N/A				Ĵ		m	J.2	hn	>	DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444							L			
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DESC FORM 193 JUL 91																			5962-	

DISTRIBUTION STATEMENT A. Approved for public release; distribution is unlimited.

5962-E130

1.2 Par	t or Identifying Num	nber (PIN). The complete	PIN shall be as s	hown in the following ex	ample:
	5%2-88658	01	x	x	•
		$\overline{1}$	<u> </u>	Ť	
	Drawing number		ase outline See 1.2.2)	Lead finish per MIL-H-38534	
1.2.1 <u>De</u>	evice type(s). The	device type(s) shall ide			
	Device type	Generic number	<u>Cir</u>	cuit function	
	01	AD578SD	A/D converter	, 12 bit, high speed	
	02	AD578TD	A/D converter	, 12 bit, high speed	
	03 04	AD578ZSD AD578ZTD		 , 12 bit, high speed , 12 bit, high speed 	
1.2.2 <u>Ca</u>	<u>ase outline(s)</u> . The	e case outline(s) shall b	e as designated ir	appendix C of MIL-M-385	10, and as follows
	Outline letter		Case outl	ine	
	x	See figure 1 (32-	lead, 1.640" x .60	05" x .280"), dual-in-lin	e package
1.3 <u>Abs</u>	olute maximum rating	<u>ls</u> .			
Supply ve	oltages (±V _{CC})			– – – – ±18 V dc	
Logic sup	oply voltage (+V _{DD})	28)		+7 V dc	
Digital				±25 V dc +5.5 V dc	
					C
		, 10 seconds)		– – – – +300°C	
Junctio	resistance: on-to-case (@) _			8°c/W	
Junctio Junctio	on-to-ambient (Θ_{A}) on temperature (T_{A})			25°C/W +175°C	
	ommended operating o				
1.4 <u>Rec</u>					
	oltage range (±V _{ac});				
Supply vo Device	oltage range (±V _{CC}): types 01 and 02 -			±13.5 V dc to	±16.5 V dc
Supply vo Device Device	types 01 and 02 [°] - types 03 and 04 -			±11.4 V dc to	±12.6 V dc
Supply vo Device Device	types 01 and 02 [°] - types 03 and 04 -			±11.4 V dc to	±12.6 V dc +5.25 V dc
Supply vo Device Device Logic su Ambient o	types 01 and 02°°- types 03 and 04 - oply voltage range (operating temperatur			±11.4 V dc to	±12.6 V dc +5.25 V dc
Supply vo Device Device Logic sup Ambient o 2. APPL	types 01 and 02°- types 03 and 04 - oply voltage range (operating temperatur ICABLE DOCUMENTS	(+V _{DD})		±11.4 V dc to +4.75 V dc to 55°C to +125°	±12.6 V dc +5.25 V dc C
Supply vo Device Device Logic sup Ambient o 2. APPL 2.1 <u>Govo</u> andard o	types 01 and 02°- types 03 and 04 - oply voltage range (operating temperatur ICABLE DOCUMENTS ernment specificatio f the issue listed	(+V _{DD}) re range (T _A)	otherwise specifi	<pre> ±11.4 V dc to +4.75 V dc to 55°C to +125° ed, the following specif Index of Specifications</pre>	±12.6 V dc +5.25 V dc C
Supply vo Device Device Logic sup Ambient o 2. APPL 2.1 <u>Govo</u> andard o	types 01 and 02°- types 03 and 04 - oply voltage range (operating temperatur ICABLE DOCUMENTS ernment specificatio f the issue listed - in the solicitation,	(+V _{DD}) re range (T _A)	otherwise specifi	<pre> ±11.4 V dc to +4.75 V dc to 55°C to +125° ed, the following specif Index of Specifications</pre>	±12.6 V dc +5.25 V dc C
Supply or Device Device Logic sup Ambient of 2. APPL: 2.1 <u>Gove</u> andard or Decified	types 01 and 02°- types 03 and 04 - oply voltage range (operating temperatur ICABLE DOCUMENTS <u>ernment specificatic</u> f the issue listed - in the solicitation, CATIONS	(+V _{DD}) re range (T _A)	otherwise specifi	<pre> ±11.4 V dc to +4.75 V dc to 55°C to +125° ed, the following specif Index of Specifications</pre>	±12.6 V dc +5.25 V dc C
Supply or Device Device Logic sup Ambient of 2. APPL 2.1 <u>Gov</u> candard of SPECIFIC MILIT/	types 01 and 02°- types 03 and 04 - oply voltage range (operating temperatur ICABLE DOCUMENTS <u>ernment specificatic</u> f the issue listed - in the solicitation, CATIONS	(+V _{DD}) re range (T _A)	otherwise specifi rtment of Defense wing to the extent	 ±11.4 V dc to +4.75 V dc to 55°C to +125° ed, the following specifindex of Specifications specified herein. 	±12.6 V dc +5.25 V dc C
Supply or Device Device Logic sup Ambient of 2. APPL 2.1 <u>Gov</u> andard of specified SPECIFIC MILIT/	types 01 and 02°- types 03 and 04 - opply voltage range (opperating temperatur ICABLE DOCUMENTS ernment specificatic f the issue listed - in the solicitation, CATIONS ARY IL-M-38510 -	(+V _{DD}) re range (T _A) ons and standard. Unless in that issue of the Depar form a part of this draw Microcircuits, General	otherwise specifi rtment of Defense wing to the extent	 ±11.4 V dc to +4.75 V dc to 55°C to +125° ed, the following specifindex of Specifications specified herein. 	±12.6 V dc +5.25 V dc C
Supply or Device Device Logic sup Ambient of 2. APPL 2.1 <u>Gov</u> andard of SPECIFIC MILIT/	types 01 and 02°- types 03 and 04 - opply voltage range (opperating temperatur ICABLE DOCUMENTS ernment specificatic f the issue listed - in the solicitation, CATIONS ARY IL-M-38510 -	(+V _{DD}) re range (T _A)	otherwise specifi rtment of Defense wing to the extent	 ±11.4 V dc to +4.75 V dc to 55°C to +125° ed, the following specifindex of Specifications specified herein. 	±12.6 V dc +5.25 V dc C
Supply or Device Device Logic sup Ambient of 2. APPL 2.1 <u>Gov</u> andard of SPECIFIC MILIT/	types 01 and 02°- types 03 and 04 - opply voltage range (opperating temperatur ICABLE DOCUMENTS ernment specificatic f the issue listed - in the solicitation, CATIONS ARY IL-M-38510 -	(+V _{DD}) re range (T _A)	otherwise specifi rtment of Defense wing to the extent	 ±11.4 V dc to +4.75 V dc to 55°C to +125° ed, the following specifindex of Specifications specified herein. 	±12.6 V dc +5.25 V dc C
Supply or Device Device Logic sup Ambient of 2. APPL 2.1 <u>Gov</u> andard of specified SPECIFIC MILIT/	types 01 and 02°- types 03 and 04 - opply voltage range (opperating temperatur ICABLE DOCUMENTS ernment specificatic f the issue listed - in the solicitation, CATIONS ARY IL-M-38510 -	(+V _{DD}) re range (T _A)	otherwise specifi rtment of Defense wing to the extent	 ±11.4 V dc to +4.75 V dc to 55°C to +125° ed, the following specifindex of Specifications specified herein. 	±12.6 V dc +5.25 V dc C
Supply or Device Device Logic sup Ambient of 2. APPL 2.1 <u>Gov</u> andard of specified SPECIFIC MILIT/	types 01 and 02°- types 03 and 04 - oply voltage range 0 operating temperatur ICABLE DOCUMENTS ernment specificatic f the issue listed - in the solicitation, CATIONS ARY IL-M-38510 - IL-H-38534 -	(+V _{DD}) re range (T _A) in that issue of the Depar form a part of this draw Microcircuits, General Hybrid Microcircuits, G	otherwise specifi rtment of Defense wing to the extent	 ±11.4 V dc to +4.75 V dc to 55°C to +125° ed, the following specifindex of Specifications specified herein. 	±12.6 V dc +5.25 V dc C ications and and Standards
Supply or Device Device Logic sup Ambient of 2. APPL 2.1 <u>Gov</u> candard of SPECIFIC MILIT/	types 01 and 02°- types 03 and 04 - opply voltage range (opperating temperatur ICABLE DOCUMENTS ernment specificatic f the issue listed - in the solicitation, CATIONS ARY IL-M-38510 -	(+V _{DD}) re range (T _A) ons and standard. Unless in that issue of the Depar form a part of this draw Microcircuits, General Hybrid Microcircuits, G	otherwise specifi rtment of Defense wing to the extent Specification for General Specificat	 ±11.4 V dc to +4.75 V dc to 55°C to +125° ed, the following specifindex of Specifications specified herein. 	±12.6 V dc +5.25 V dc C
Supply vo Device Device Logic sup Ambient of 2. APPL: 2.1 <u>Gov</u> tandard of becified SPECIFIC MILIT/ M.	types 01 and 02°- types 03 and 04 - opply voltage range 0 coperating temperatur ICABLE DOCUMENTS <u>ernment specificatic</u> f the issue listed in the solicitation, CATIONS ARY IL-M-38510 - IL-H-38534 - STANDAR MILITARY	<pre>(+V_{DD})</pre>	otherwise specifi rtment of Defense wing to the extent Specification for General Specificat	 ±11.4 V dc to +4.75 V dc to 55°C to +125° ed, the following specifindex of Specifications specified herein. 	±12.6 V dc +5.25 V dc C ications and and Standards

STANDARD

≦询"5962+&865801XA"供应商

MIL-STD-883 - Test Methods and Procedures for Microelectronics.

(Copies of the specifications and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 <u>Order of precedence</u>. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

3. REQUIREMENTS

3.1 <u>Item requirements</u>. The individual item requirements shall be in accordance with MIL-H-38534 and as specified herein.

3.2 <u>Design, construction, and physical dimensions</u>. The design, construction, and physical dimensions shall be as specified in MIL-H-38534 and herein.

3.2.1 <u>Case outline(s)</u>. The case outline(s) shall be in accordance with 1.2.2 and figure 1.

3.2.2 <u>Terminal connections</u>. The terminal connections shall be as specified on figure 2.

3.2.3 Logic diagram. The logic diagram shall be as specified on figure 3.

3.2.4 Timing diagram. Timing diagram shall be as specified on figure 4.

3.2.5 <u>Digital output data</u>. Digital output data shall be as specified on figure 5.

3.3 <u>Electrical performance characteristics</u>. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and shall apply over the full specified operating temperature range.

3.4 <u>Electrical test requirements</u>. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table I.

3.5 <u>Marking</u>. Marking shall be in accordance with MIL-H-38534. The part shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's PIN may also be marked as listed in QML-38534 (see 6.6 herein).

3.6 <u>Manufacturer eligibility</u>. In addition to the general requirements of MIL-H-38534, the manufacturer of the part described herein shall submit for DESC-ECT review and approval electrical test data (variables format) on 22 devices from the initial quality conformance inspection group A lot sample, produced on the certified line, for each device type listed herein. The data should also include a summary of all parameters manually tested, and for those which, if any, are guaranteed.

3.7 <u>Certificate of compliance</u>. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in QML-38534 (see 6.6 herein). The certificate of compliance submitted to DESC-ECT prior to listing as an approved source of supply shall affirm that the manufacturer's product meets the requirements of MIL-H-38534 and the requirements herein.

3.8 <u>Certificate of conformance</u>. A certificate of conformance as required in MIL-H-38534 shall be provided with each lot of microcircuits delivered to this drawing.

4. QUALITY ASSURANCE PROVISIONS

4.1 <u>Sampling and inspection</u>. Sampling and inspection procedures shall be in accordance with MIL-H-38534.

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Test	Symbol	Conditions 1/ -55°C ≤ T₄ ≤ +125°C unless otherWise specified	Group A subgroup		 	Limits	Unit
••••••••••••••••••••••••••••••••••••••					Min	Max	
ain error	V _{GE}	 10 V unipolar, 20 V bipolar,	1	ALL	-0.25	+0.25	%/FSR
		end-point electrical	1	ALL	-0.30	+0.30	
Gain drift	V _{GD}	10 V unipolar, 20 V bipolar	2, 3	01,03	-50 -30	+50 +30	ppm/°C
Jnipolar offset error	V _{OSE}	10 V unipolar	1	ALL	-0.25	+0.25	%/FSR
Jnipolar offset drift	V _{OSD}	10 V unipolar	2, 3	01,03	 <u>-15</u> -10	 +15 +10	ppm/°C
Bipolar offset error	V _{OSE}	20 V bipolar, end-point electrical	1	ALL	-0.25	+0.25	%/FSR
Bipolar offset drift	V _{OSD}	20 V bipolar	2, 3	01,03 02,04	-25 -20	+25 +20	ppm/°C
inearity error	RA	10 V unipolar, 20 V bipolar	1	ALL	-0.50	+0.50	LSB
		10 V unipolar, 20 V bipolar	2, 3	ALL	-0.75	+0.75	
Differential Linearity error	DNL	10 V unipolar, 20 V bipolar	1, 2, 3	ALL	-1.0	+1.0	+
10 V reference error	v _{RE}		1	ALL	-100	+100	mV
			2,3	ALL	-20	+20	ppm/°C
FV _{DD} Power supply sensitivity	PSRR	2/	1,2,3	ALL	-0.005	+0.005	%/%+V _{DD}
ee footnotes at en	d of table.						
	STANDARI		SIZE A			5	962-8865
DEFENSE EL		S SUPPLY CENTER		REVISION	I.EVEI	. s	HEET

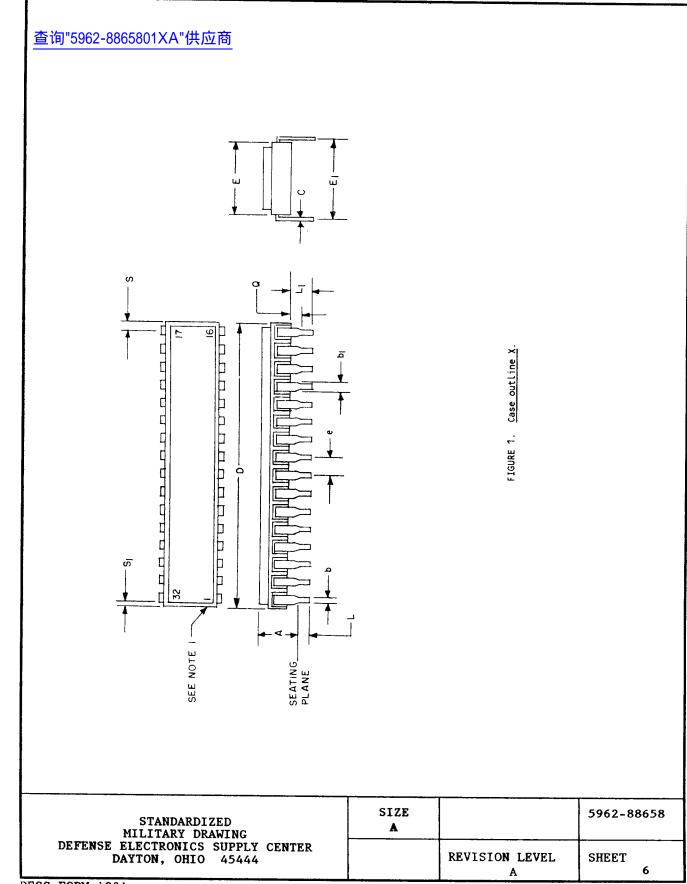
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Test	Symbol	Conditions $\frac{1}{-55^{\circ}C} \leq T_{A} \leq +125^{\circ}C$	Group A subgroups	Device types	L.	imits	Unit
	_	unless otherŵise specifi	ea		Min	Max	
±V _{CC} Power supply sensitivity	PSRR	2/	1,2,3	01,02	-0.005	+0.005	%/%±Vcc
±V _{CC} Power supply sensitivity	PSRR	2/	1,2,3	03,04	-0.007	+0.007	
Digital output high drive	v _{он}	at -80 µA I _{OH} 2/	1,2,3	ALL	2.4		V dc
Digital output low drive	v _{oL}	at 3.2 mA I _{OL} <u>2</u> /	1,2,3	ALL		0.4	
+V _{DD} Supply drain	+I _{DD}	All bits on 2/	1,2,3	ALL		150	mA
+V _{CC} Supply drain	+I _{CC}	All bits on 2/	1,2,3	ALL		8	
-V _{CC} Supply drain	-Icc	All bits on 2/ \$	1,2,3	ALL		35	
ower dissipation	PD	T _A = +25°C		ALL		715	mW
conversion speed	tc	3/	9,10,11 9,10,11	01,03 02,04		<u>6</u> 4.5	μs
2/ Subgroups 2 and Subgroups 2 and limits specified 2/ Subgroups 10 and	3 shall be 3 shall al: 1 in table 1 11 shall 1	$\pm V_{CC} = \pm 13.5$ V to ± 16.5 V for tested as part of device initiso so be tested after all design I for all lots not specificall be tested as part of device in the guaranteed to the limits sp	tial characterizat and process change y tested. Subgrou nitial characteriza	ion and ev es and sha up 1 shall ation and	ery 52 m Il be g be tes after d	weeks th uarantee ted with esign an	ereafter. d to the every lo d process

- a. Burn-in test, method 1015 of MIL-STD-883.
 - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.7 herein).
 - (2) T_A as specified in accordance with table I of method 1015 of MIL-STD-883.
- b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

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	Inc	ches	Mill	imeters	ļ
Symbol	Min	Max	Min	Max	Notes
A		.280		7.11	
b	.016	.020	0.41	0.51	
Þ ₁	.035	. 045	0.89	1.14	2
c	.009	.012	0.23	0.30	
D	1.584	1.640	40.23	41.66	
Ε	_ 580	. 605	14.73	15.37	
E ₁	.590	.610	14.99	15.49	6
e	<u>،</u> 10	DO BSC	2.54	4,7	
L	.125	. 200	3.18	5.08	
L1	. 180		4.57		
Q	.015	.060	0.38	1.52	3
s		. 098		2.49	5
s ₁	.005		0.13		5

NOTES:

Index area; a notch or a lead one indentification mark is located adjacent to lead one.
 The minimum limit for dimension b₁ may be .023 inch (0.58 mm) for all four corner leads only.
 Dimension Q shall be measured from the seating plane to the base plane.
 The basic pin spacing is .100 inch (2.54 mm) between centerlines.

- 5. Applies to all four corners.
- 6. E₁ shall be measured at the centerline of the leads.
 7. Thirty spaces.
 8. Dimensions are in inches.

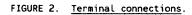
- 9. Metric equivalents are given for general information only.

FIGURE 1. <u>Case outline X</u> - Continued.

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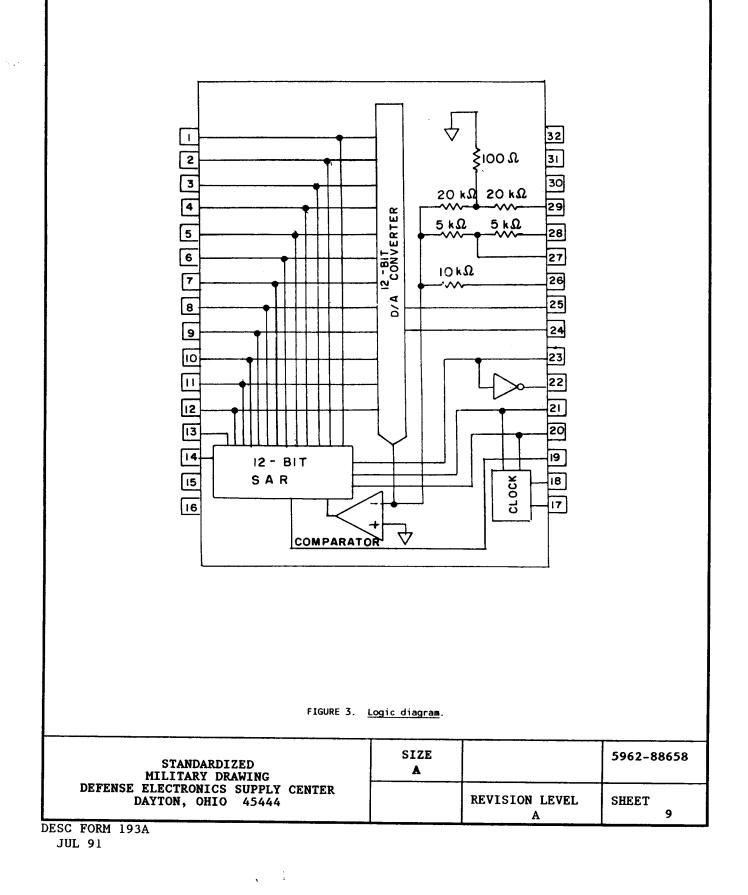
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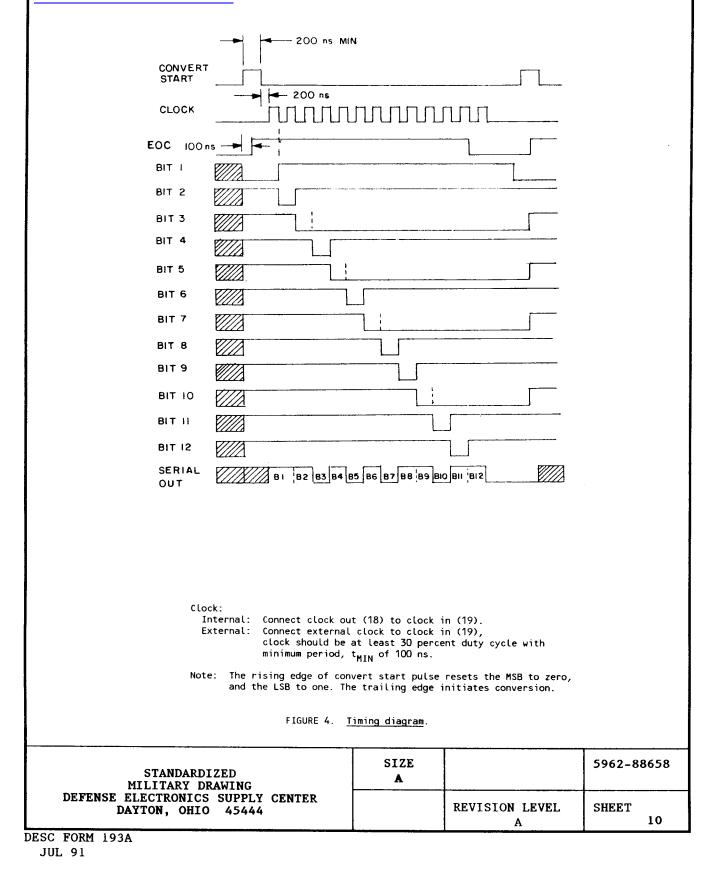
Device types	01, 02, 03, and 04
Case outline	x
Terminal number	Terminal symbol
1	BIT 12
2 3 4	BIT 11 BIT 10
5	BIT 9
5	BIT 8
6	BIT 7
7	BIT 6
8	BIT 5
9	BIT 4
10	BIT 3
11	BIT 2
12	BIT 1
13	BIT 1
14	SHORT CYCLE
15	DIGITAL GND
16	+5 V
17	CLOCK ADJ
18	CLOCK OUT
19	CLOCK IN
20	EOC
21	CONVERT START
22	SERIAL OUT
23	SERIAL OUT
24 25	REF OUT
25	GAIN (REF IN) BIPOLAR OFFSET
20	10 V SPAN INPUT
28	20 V SPAN INPUT
29	ZERO ADJ
30	ANALOG GND
31	+15 V
32	-15 V



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	Analog input - vo of quantization		Digital output code (binary for unipolar ranges; offset binary for bipolar ranges)							
0 to +10 V Range	0 to +20 V Range	-5 V to +5 V Range	-10 V to +10 V Range	B1 (MSB)						B12 LSB)
+9.9976 +9.9952 -	+19.9951 +19.9902 -	+4.9976 +4.9952 -	+9.9951 +9.9902 -			1 1 1 1 -				
- +5.0024 +5.0000 -	+10.0049 +10.0000 -	- +0.0024 +0.0000 -	- +0.0049 +0.0000 -			0 0 0 0				
- +0.0024 +0.0000	- +0.0051 +0.0000	- -4.9976 -5.0000	-9.9951 -10.0000	•		0 0 0 0				
		FIGURE 5.	Digital output data	<u>a</u> .						
STAI	NDARDIZED ARY DRAWING	FIGURE 5.	Digital output data	<u>e</u> .						5962-886

4.3 Quality conformance_inspection. Quality conformance inspection shall be in accordance with MIL-H-38534 and as specified herein. 查询"5962-8865801XA"供应商 4.3.1 <u>Group A inspection</u>. Group A inspection shall be in accordance with MIL-H-38534 and as follows:

- a. Tests shall be as specified in table II herein.
- b. Subgroups 4, 5, 6, 7, and 8 shall be omitted.
- 4.3.2 Group B inspection. Group B inspection shall be in accordance with MIL-H-38534.
- 4.3.3 Group C inspection. Group C inspection shall be in accordance with MIL-H-38534 and as follows:
 - a. End-point electrical parameters shall be as specified in table II herein.
 - b. Steady-state life test conditions, method 1005 of MIL-STD-883.
 - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.7 herein).
 - (2) T_A as specified in accordance with table I of method 1005 of MIL-STD-883.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

MIL-STD-883 test requirements	Subgroups (per method 5008, group A test table)
Interim electrical parameters	1
Final electrical test parameters	1*, 2, 3, 9
Group A test requirements	1, 2, 3, 9, 10,11
Group C end-point electrical parameters	1, 2, 3
*PDA applies to subgroup 1.	

TABLE II. <u>Electrical test requirements</u>.

4.3.4 Group D inspection. Group D inspection shall be in accordance with MIL-H-38534.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-H-38534.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for original equipment design applications and logistic support of existing equipment.

6.2 <u>Replaceability</u>. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.3 <u>Configuration control of SMD's</u>. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished in accordance with MIL-STD-481 using DD Form 1693, Engineering Change Proposal (Short Form).

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6.5 <u>Comments</u>. Comments on this drawing should be directed to DESC-ECT, Dayton, Ohio 45444, or telephone (513) 296-5374.

6.6 <u>Approved sources of supply</u>. Approved sources of supply are listed in QML-38534. Additional sources will be added to QML-38534 as they become available. The vendors listed in QML-38534 have agreed to this drawing and a certificate of compliance (see 3.7 herein) has been submitted to and accepted by DESC-ECT.

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